

TSMC-02-544

December 1, 2003

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/657,503 09/08/03 |
Jaw-Jung Shin et al.
PHASE SHIFT ASSIGNMENTS FOR
| ALTERNATE PSM |
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INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56. Copies of each document is included herewith.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on December 8, 2003.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

SB Ackerman 12/8/03

TSMC-02-544

U.S. Patent 6,249,904 to Cobb, "Method and Apparatus for Submicron IC Design Using Edge Fragment Tagging to Correct Edge Placement Distortion," discloses a process to correct edge placement distortion.

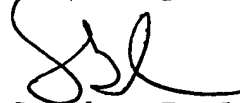
U.S. Patent 6,057,064 to Lin, "Double-Alternating Phase-Shifting Mask," describes a double alternating PSM.

U.S. Patent 6,396,158 to Travis et al., "Semiconductor Device and a Process for Designing a Mask," discloses a mask process including assist features.

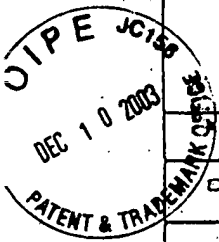
U.S. Patent 6,312,856 to Lin, "Half-Tone Phase Shift Mask for Fabrication of Poly Line," reveals a PSM with assist features.

U.S. Patent 6,303,252 to Lin, "Reticle Having Assist Feature Between Semi-Dense Lines," describes a reticle having an assist feature between semi-dense lines.

Sincerely,

A handwritten signature in black ink, appearing to be 'SBA', written over the printed name.

Stephen B. Ackerman,
Reg. No. 37761



Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	Document Number (Copies) TSMC-02-544	Application Number 10/657,503
	Applicant Jaw-Jung Shin et al.	
	Filing Date 09/08/03	Group Art Unit

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6 249 904	6/19/01	Cobb	716	21	4/30/99
	6 057 064	5/2/00	Lin	430	5	5/21/98
	6 396 158	5/29/02	Travis et al.	257	784	6/29/99
	6 312 856	11/6/01	Lin	430	5	12/7/99
	6 303 252	10/16/01	Lin	430	5	12/27/99

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.